

TOSHIBA PHOTOCOUPLER GaAlAs IRED & PHOTO IC

TLP559(IGM)

TRANSISTOR INVERTER **INVERTER FOR AIR CONDITIONER** LINE RECEIVER **IPM INTERFACES**

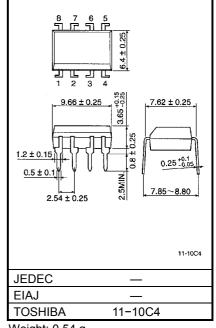
The TOSHIBA TLP559(IGM) consists of a GaAIAs high-output light emitting diode and a high speed detector of one chip photo diodetransistor.

This unit is 8-lead DIP package.

TLP559(IGM) has no internal base connection, and a Faraday shield integrated on the photodetector chip provides an effective common mode noise transient immunity.

TLP559(IGM) guarantees minimum and maximum of propagation delay time, switching time dispersion, and high common mode transient immunity. There for TLP559(IGM) is suitable for isolation interface between IPM(Intelligent Power Module) and control IC circuits in motor control application.

- Isolation Voltage : 2500 Vrms (Min)
- Common Mode Transient Immunity



Weight: 0.54 g

Switching Time

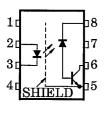
:±10kV/µs (Min) @V_{CM} = 1500 V

: t_{pHL} , t_{pLH} = 0.1µs (Min) = 0.8µs (Max)

 $@I_F = 10 \text{ mA}$, $V_{CC} = 15 \text{ V}$, $R_L = 20 \text{ k}\Omega$, $Ta = 25^{\circ}C$

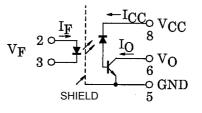
- Switching Time Dispersion : 0.7µs (Max) (|tpLH-tpHL|)
- TTL Compatible
- UL Recognized : UL1577, File No. E67349

PIN CONFIGURATION(Top view)



1:N.C. 2:ANODE 3:CATHODE 4:N.C. **5:EMITTER** 6:COLLECTOR 7:N.C. 8:V_{CC}

SCHEMATIC



Unit: mm

MAXIMUM RATINGS (Ta = 25°C)

	CHARACTERISTIC		SYMBOL	RATING	UNIT
	Forward Current	(Note 1)	١ _F	25	mA
	Pulse Forward Current	(Note 2)	I _{FP}	50	mA
LED	Peak Transient Forward Current	(Note 3)	I _{FPT}	1	А
—	Reverse Voltage		V _R	5	V
	Diode Power Dissipation	(Note 4)	PD	45	mW
	Output Current		Ι _Ο	8	mA
OR	Peak Output Current		I _{OP}	16	mA
DETECTOR	Output Voltage		Vo	-0.5~20	V
DET	Supply Voltage		V _{CC}	-0.5~30	V
	Output Power Dissipation	(Note 5)	PO	100	mW
Ope	Operating Temperature Range			-55~100	°C
Stor	age Temperature Range	T _{stg}	-55~125	°C	
Lea	Lead Solder Temperature(10s) (Note 6)			260	°C
Isola	ation Voltage(AC,1min.,R.H.≤60%,Ta=25°C)	BVS	2500	Vrms	

(Note 1) Derate 0.5mA above 70°C.

(Note 2) 50% duty cycle,1ms pulse width.

Derate -1.0mA/°C above 70°C.

(Note 3) Pulse width PW≤1µs,300pps.

(Note 4) Derate 0.9mW/°C above 70°C.

(Note 5) Derate 2mW/°C above 70°C.

(Note 6) Soldering portion of lead : up to 2mm from the body of the device.

(Note 7) Device considerd a two terminal device : pins1,2,3 and 4 shorted together and pins5,6,7 and 8 shorted together.

ELECTRICAL CHARACTERISTICS (Ta = 25°C)

CHARACTERISTIC		SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT	
LED	Forward Voltage	V _F	I _F = 16 mA	_	1.65	1.85	V	
	Forward Voltage Temperature Coefficient	∆V _F /∆Ta	I _F = 16 mA		-2	_	mV /°C	
	Reverse Current	I _R	V _R = 5 V	_	—	10	μA	
	Capacitance between Terminal	СТ	V = 0, f = 1 MHz	_	45	_	pF	
DETECTOR	High Level Output Current	I _{OH (1)}	I _F = 0 mA, V _{CC} = V _O = 5.5 V	_	3	500	nA	
		I _{OH (2)}	$I_F = 0 \text{ mA}, V_{CC} = 30 \text{ V}$ $V_O = 20 \text{ V}$	_	_	5	μA	
		I _{OH}	I _F = 0 mA, V _{CC} = 30 V V _O = 20 V, Ta = 70°C	_	_	50	μΑ	
	High Level Supply Voltage	ICCH	I _F = 0 mA, V _{CC} = 30 V	_	0.01	1	μA	
	Supply Voltage	V _{CC}	I _{CC} = 0.01 mA	30			V	
	Output Voltage	Vo	I _O = 0.5 mA	20		_	V	

COUPLED ELECTRICAL CHARACTERISTICS (Ta = 25°C)

CHARACTERISTIC	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT	
Current Transfer Ratio	I _O / I _F	I _F = 10 mA, V _{CC} = 4.5 V V _O = 0.4 V	25	35	75	%	
	10 / 16	I _F = 10 mA, V _{CC} = 4.5 V V _O = 0.4 V, Ta = −25~100°C	15	_	_	70	
Low Level Output Voltage	V _{OL}	I _F = 16 mA, V _{CC} = 4.5 V I _O = 2.4 mA		_	0.4	V	

ISOLATION CHARACTERISTICS (Ta = 25°C)

CHARACTERISTIC	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Capacitance Input to Output	CS	V = 0, f = 1 MHz	_	0.8	—	pF
Isolation Resistance	R _S	R.H.≤60%, V _S = 500 V	5×10 ¹⁰	10 ¹⁴	_	Ω
		AC , 1minute	2500	-	_	Vrms
Isolation Voltage	BVS	AC , 1second, in oil	_	5000	_	VIIIS
		DC, 1minute,in oil	_	5000	_	Vdc

SWITCHING CHARACTERISTICS (Ta = 25° C, V_{CC} = 15 V)

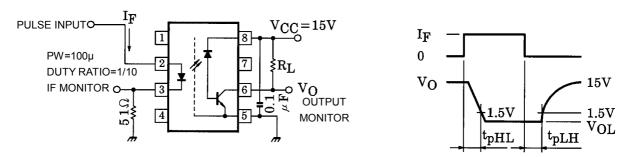
CHARACTERISTIC	SYMBOL	TEST CIR- CUIT	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
	^t рНL t _{pLH}	- 1	I _F = 10 mA, R _L = 20 kΩ	0.1	0.45	0.8	µs µs
Propagation Delay Time $(H \rightarrow L)$			I _F = 10 mA, R _L = 20 kΩ Ta = 0~85°C	0.1	0.45	0.9	
Propagation Delay Time (L \rightarrow H)			I _F = 10 mA, R _L = 20 kΩ Ta = −25~100°C	0.1	0.45	1.0	
			I _F = 10 mA, R _L = 20 kΩ	_	0.15	0.7	
Switching Time Dispersion between ON	t _{pLH} −t _{pHL}		I _F = 10 mA, R _L = 20 kΩ Ta = 0~85°C	_	0.25	0.8	
and OFF			I _F = 20 mA, R _L = 20 kΩ Ta = −25~100°C	_	0.25	0.9	
Common Mode Transient Immunity at Logic High Output (Note 8)	CM _H	- 2	$I_F = 0$ mA, V _{CM} = 1500 V _{p-p} , R _L = 20 kΩ	10000	15000	_	V /µs
Common Mode Transient Immunity at Logic Low Output (Note 8)	CML		I_F =10 mA, V _{CM} = 1500 V _{p-p} , R _L = 20 kΩ	-10000	-15000	_	V /µs

 $\begin{array}{ll} \mbox{(Note 8)} & \mbox{CM}_L \mbox{ is the maximum rate of fall of the common mode voltage that can be} \\ & \mbox{sustained with the output voltage in the logic low state(Vo<1V).} \\ & \mbox{CM}_H \mbox{ is the maximum rate of rise of the common mode voltage that can be} \\ & \mbox{sustained with the output voltage in the logic high state(Vo>4V).} \end{array}$

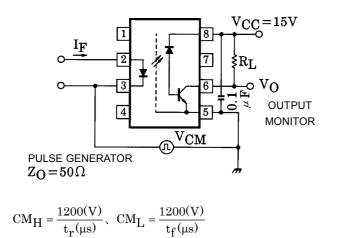
(Note 9) Maximum electrostatic discharge voltage for any pins : 100V(C=200pF,R=0)

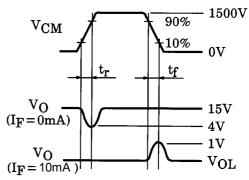
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TEST CIRCUIT 1 : Switching time test circuit



TEST CIRCUIT 2 : Common mode noise immunity test circuit





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